

<b>Notice of References Cited</b>	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	09/853,319	ONAKA, HIROSHI	
	Examiner	Art Unit	Page 1 of 1
	Chau M Nguyen	2633	

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,559,996	05-2003	Miyamoto et al.	398/183
B	US-6,078,416	06-2000	Yano, Yutaka	398/154
C	US-6,108,125	08-2000	Yano, Yutaka	398/154
D	US-5,801,862	09-1998	Desurvire et al.	398/155
E	US-			
F	US-			
G	US-			
H	US-			
I	US-			
J	US-			
K	US-			
L	US-			
M	US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N	JP 2000059300 A	02-2000	Japan	NISHIZAWA, HIDEKI	H04B 10/00
O					
P					
Q					
R					
S					
T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.